

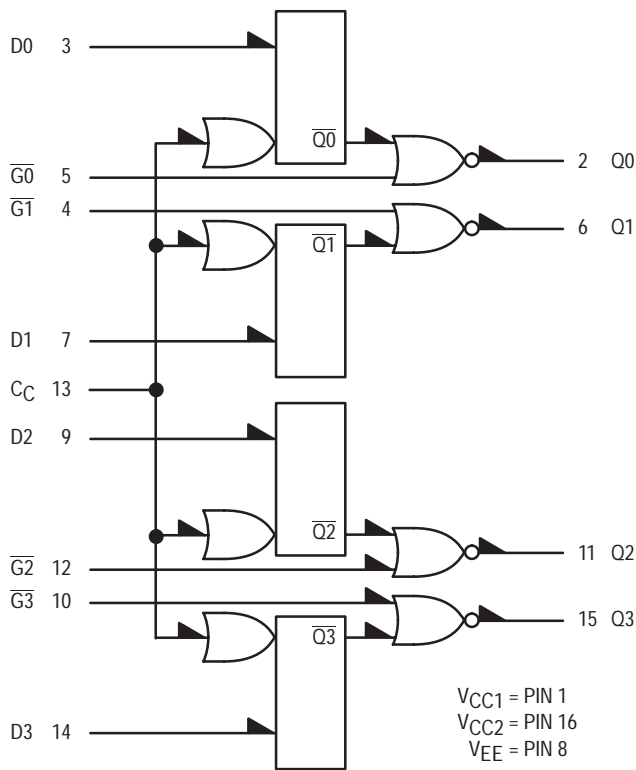
MC10168

Quad Latch

The MC10168 is a Quad Latch with common clocking to all four latches. Separate output enabling gates are provided for each latch, allowing direct wiring to a bus. When the clock is high, outputs will follow the D inputs. Information is latched on the negative-going transition of the clock.

- $P_D = 310 \text{ mW typ/pkg (No Load)}$
- $t_{pd} = G \text{ to } Q = 2 \text{ ns typ}$
 $D \text{ to } Q = 3 \text{ ns typ}$
 $C \text{ to } Q = 4 \text{ ns typ}$
- $t_r, t_f = 2.0 \text{ ns typ (20\%–80\%)}$

LOGIC DIAGRAM



TRUTH TABLE

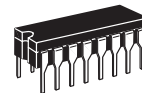
\overline{G}	C	D	Q_{n+1}
H	X	X	L
L	L	X	Q_n
L	H	L	L
L	H	H	H



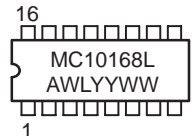
ON Semiconductor

<http://onsemi.com>

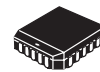
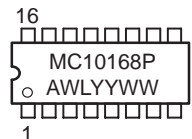
MARKING DIAGRAMS



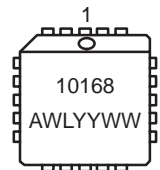
CDIP-16
L SUFFIX
CASE 620



PDIP-16
P SUFFIX
CASE 648

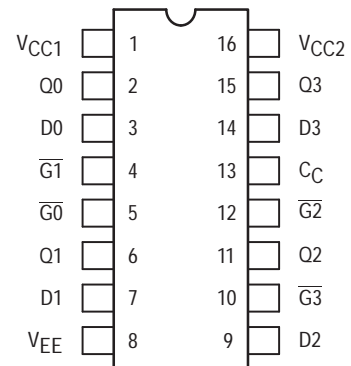


PLCC-20
FN SUFFIX
CASE 775



A = Assembly Location
WL = Wafer Lot
YY = Year
WW = Work Week

DIP PIN ASSIGNMENT



Pin assignment is for Dual-in-Line Package.
For PLCC pin assignment, see the Pin Conversion Tables on page 18.

ORDERING INFORMATION

Device	Package	Shipping
MC10168L	CDIP-16	25 Units / Rail
MC10168P	PDIP-16	25 Units / Rail
MC10168FN	PLCC-20	46 Units / Rail

MC10168

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Pin Under Test	Test Limits							Unit	
			-30°C		+25°C			+85°C			
			Min	Max	Min	Typ	Max	Min	Max		
Power Supply Drain Current	I_E	8		82		60	75		82	mAdc	
Input Current	I_{inH}	3,7,9,14 4,5,10,12 13		390 425 460			245 265 290		245 265 290	μ Adc	
	I_{inL}	*	0.5		0.5			0.3		μ Adc	
Output Voltage Logic 1	V_{OH}	2 6	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc	
Output Voltage Logic 0	V_{OL}	2 6	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc	
Threshold Voltage Logic 1	V_{OHA}	2 6	-1.080 -1.080		-0.980 -0.980			-0.910 -0.910		Vdc	
Threshold Voltage Logic 0	V_{OLA}	2 6		-1.655 -1.655			-1.630 -1.630		-1.595 -1.595	Vdc	
Switching Times (50 Ω Load)											
Propagation Delay	Data	t_{3+2+}	2	1.0	5.6	1.0	3.0	5.4	1.1	5.9	ns
	Gate	t_{5-2+}	2	1.0	3.2	1.0	2.0	3.1	1.0	3.4	
	Clock	t_{13+2+}	2	1.0	5.8	1.0	4.0	5.6	1.2	6.2	
Setup Time		t_{3+13+}	2	2.5		2.5			2.5		
Hold Time		t_{13+3+}	2	1.0		1.0			1.0		
Rise Time (20 to 80%)		t_{2+}	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	
Fall Time (20 to 80%)		t_{2-}	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	

* Individually test each input applying V_{IH} or V_{IL} to input under test.

MC10168

ELECTRICAL CHARACTERISTICS (continued)

@ Test Temperature			TEST VOLTAGE VALUES (Volts)					(V _{CC}) Gnd	
			V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}		
			-30°C	-0.890	-1.890	-1.205	-1.500		-5.2
			+25°C	-0.810	-1.850	-1.105	-1.475		-5.2
+85°C	-0.700	-1.825	-1.035	-1.440	-5.2				
Characteristic	Symbol	Pin Under Test	TEST VOLTAGE APPLIED TO PINS LISTED BELOW						
			V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}		
Power Supply Drain Current	I _E	8					8	1, 16	
Input Current	I _{inH}	3,7,9,14	*				8	1, 16	
		4,5,10,12	*				8	1, 16	
		13	13				8	1, 16	
Output Voltage	Logic 1	V _{OH}	2	3, 13				8	1, 16
			6	7, 13				8	1, 16
Output Voltage	Logic 0	V _{OL}	2	3, 5				8	1, 16
			6	4, 7				8	1, 16
Threshold Voltage	Logic 1	V _{OHA}	2	13		3		8	1, 16
			6	13		7		8	1, 16
Threshold Voltage	Logic 0	V _{OLA}	2	13			3	8	1, 16
			6	13			7	8	1, 16
Switching Times (50Ω Load)				+1.11V		Pulse In	Pulse Out	-3.2 V	+2.0 V
Propagation Delay	Data	t ₃₊₂₊	2			3	2	8	1, 16
	Gate	t ₅₋₂₊	2			5	2	8	1, 16
	Clock	t ₁₃₊₂₊	2			13	2	8	1, 16
Setup Time		t ₃₊₁₃₊	2					8	1, 16
Hold Time		t ₁₃₊₃₊	2					8	1, 16
Rise Time (20 to 80%)		t ₂₊	2			3	2	8	1, 16
Fall Time (20 to 80%)		t ₂₋	2			3	2	8	1, 16

* Individually test each input applying V_{IH} or V_{IL} to input under test.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50-ohm resistor to -2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.